

Search Notes

Application/Control No.

10/670,470

Examiner

Paul D. Kim

Applicant(s)/Patent under
Reexamination

SHIMAZAWA ET AL.

Art Unit

3729

SEARCHED

Class	Subclass	Date	Examiner
29	603.07 603.13- 603.16 603.18	2/28/2006	PK
360	324.1		
	324.11		
	324.12		
	324.2 316		
427	127-131		
216	22,48		
204	192.15	✓	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PGPub Text Search See attachment		2/28/2006	PK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reviewed Parent Application 09/920,821 (US PAT. 6,657,826)	2/28/2006	PK
Text Search EAST/NPL (IEEE) with PGPub	2/28/2006	PK